Abstracts

Noise Waves, a Concept Leading to Deep Insight and Accurate Noise Characterization

R. Meys and M. Milecan. "Noise Waves, a Concept Leading to Deep Insight and Accurate Noise Characterization." 1982 MTT-S International Microwave Symposium Digest 82.1 (1982 [MWSYM]): 351-353.

Rapid advances in GaAs FET technology have raised the problem of accurately determining the noise performance of rather low gain devices at increasing frequencies. We propose a solution based on the description of noise through correlated waves that avoids many difficulties associated with classical methods (source mismatch error, biased optimum, unpredictable tuner losses, no consistency checks). It lends itself to both automation and computer implementation.

❑ Return to main document.

Click on title for a complete paper.